

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3	((("5095357") or ("5446311") or ("5541442")).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/28 10:05
L2	1	("5459368").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/28 11:25
L3	1	("6037649").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/28 12:17
L4	1	("4048594").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/28 12:46
L5	1572	induct\$3 with parallel with (amplifier gain adj stage)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/28 12:47
S1	2139	((257/531,E21.02) or (336/84R, 84C)).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/28 10:05
S6	290	(shield cage Faraday EMI electromagneti\$3) same (well hole opening aperture) and induct\$3 and (chip IC die integrated adj circuit) and substrate and (UMB under adj bump adj metallization under adj bump adj metal\$3 (aluminum and bump))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 10:53
S7	1	("6037649").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/22 10:46
S8	231211	((("257") or ("438"))).CLAS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/22 14:12
S9	8363	S8 and (IC integrated adj circuit chip die) and (interconnect trace redistribution adj layer metal adj layer) and (shield Faraday EMI electromagnetic)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:14

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S10	5091	S8 and (IC integrated adj circuit chip die) and (interconnect trace redistribution adj layer metal adj layer) and (shield Faraday EMI electromagnetic) and (circuit adj element capacit\$3 induct\$3 passive adj element)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:16
S11	4437	S8 and (IC integrated adj circuit chip die) and (interconnect trace redistribution adj layer metal adj layer) and (shield Faraday EMI electromagnetic) and (circuit adj element capacit\$3 induct\$3 passive adj element) and (via hole)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/27 15:30
S12	1348	S8 and (IC integrated adj circuit chip die) and (interconnect trace redistribution adj layer metal adj layer) and (shield Faraday EMI electromagnetic) and (circuit adj element capacit\$3 induct\$3 passive adj element) and (via hole) and (amplifier gain)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/22 14:18
S15	2140	((257/531,E21.02) or (336/84R, 84C)).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/23 10:46
S16	283	S15 and (shield cage Faraday EMI electromagnet\$3) and (via hole plug) and induct\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/23 10:46
S17	235	(shield cage Faraday EMI electromagnet\$3) and (via hole plug) and (chip IC die integrated adj circuit) and induct\$3 and capacit\$3 and (passivat\$3) and (bump BGA ball near solder)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/27 15:31
S18	1404	(shield cage Faraday EMI electromagnet\$3) and (via hole plug) and (chip IC die integrated adj circuit) and induct\$3 and capacit\$3 and (bump BGA ball near solder)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/23 11:22
S20	977	(shield cage Faraday EMI ((electromagnet\$3 electric\$2) near (barri\$4 protect\$3 prevent\$3))) and (via hole plug) and (chip IC die integrated adj circuit) and induct\$3 and capacit\$3 and (bump BGA ball near solder)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/24 13:40

## EAST Search History

S21	1	("6377464").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/28 11:04
S23	1	("6501169").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/27 15:28
S26	4	(("6489647") or ("6455885") or ("6303423") or ("6383916")).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/27 15:44
S27	1	("6037649").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/03/27 17:55